

AOTF780A70NL

700V, aMOS5[™] N-Channel Power Transistor

General Description

- Proprietary $\alpha MOS5^{TM}$ technology
- Low $R_{DS(ON)}$
- Optimized switching parameters for better EMI performance
- Enhanced body diode for robustness and fast reverse recovery

Applications

 PFC and PWM stages (Flyback, LLC) of Adapter, PC Silverbox, Server, Gaming Power Supply, Industrial, TV, Lighting

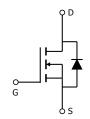
Product Summary

 $\begin{array}{lll} V_{DS} @ T_{j,max} & 800V \\ I_{DM} & 28A \\ R_{DS(ON),max} & < 0.78\Omega \\ Q_{g,typ} & 11.5nC \\ E_{oss} @ 400V & 1.4 \mu J \end{array}$

100% UIS Tested 100% R_g Tested







Orderable Part Number Pa		Package Type	Form	Minimum Order Quantity		
AOTF780A70NL		TO220FNL	Tube	1000		
Absolute Maximum	Ratings T _A =25°C	unless otherwise noted				
Parameter		Symbol	Maximum	Units		
Drain-Source Voltage		V _{DS}	700	V		
Gate-Source Voltage		V_{GS}	±20	V		
Gate-Source Voltage (dynamic) AC(f>1Hz)		1Hz) V _{GS}	±30	V		
Continuous Drain	T _C =25°C	ı	7*			
Current	T _C =100°C	I _D	4.5*	A		
Pulsed Drain Current ^C		I _{DM}	28			
Avalanche Current ^C L=1mH		I _{AR}	1.7	A		
Repetitive avalanche energy ^C		E _{AR}	1.5	mJ		
Single pulsed avalanche energy ^G		E _{AS}	11	mJ		
MOSFET dv/dt ruggedness		dv/dt	100	V/ns		
Peak diode recovery dv/dt		3.7,31	20			
	T _C =25°C	P _D	25	W		
Power Dissipation ^B	Derate above 25	s.c , p	0.2	W/°C		
Junction and Storage Temperature Range		nge T _J , T _{STG}	-55 to 150	°C		
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds		g T _L	300	°C		
Thermal Characteris	stics					
Parameter		Symbol	Maximum	Units		
Maximum Junction-to	-Ambient A,D	$R_{\theta JA}$	65	°C/W		
Maximum Junction-to	-Case	$R_{\theta JC}$	5.0	°C/W		

^{*} Drain current limited by maximum junction temperature.



Electrical Characteristics (T_.=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
STATIC I	PARAMETERS					
BV _{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0V, T_J = 25 ^{\circ} C$	700			V
		$I_D=250\mu A, V_{GS}=0V, T_J=150^{\circ}C$		800		
BV _{DSS} /∆TJ	Breakdown Voltage Temperature Coefficient	I _D =250μA, V _{GS} =0V		0.56		V/°C
I _{DSS}	Zoro Coto Voltago Proin Current	V _{DS} =700V, V _{GS} =0V			1	μΑ
	Zero Gate Voltage Drain Current	V _{DS} =560V, T _J =125°C			10	
I _{GSS}	Gate-Body leakage current	$V_{DS}=0V$, $V_{GS}=\pm20V$			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =5V _, I _D =250μA	2.9	3.5	4.1	V
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =1.4A		0.7	0.78	Ω
g _{FS}	Forward Transconductance	V _{DS} =10V, I _D =1.4A		3		S
V _{SD}	Diode Forward Voltage	I _S =1.4A,V _{GS} =0V		0.8	1.2	V
Is	Maximum Body-Diode Continuous Current				7	Α
I _{SM}	Maximum Body-Diode Pulsed Current	C			28	Α
DYNAMI	CPARAMETERS					
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =100V, f=1MHz		675		pF
Coss	Output Capacitance	V _{GS} -0V, V _{DS} -100V, 1-11VII 12		18		pF
C _{o(er)}	Effective output capacitance, energy related H			16.5		pF
C _{o(tr)}	Effective output capacitance, time related	-V _{GS} =0V, V _{DS} =0 to 400V, f=1MHz		72		pF
C _{rss}	Reverse Transfer Capacitance	V _{GS} =0V, V _{DS} =100V, f=1MHz		1.8		pF
R_g	Gate resistance	f=1MHz		3.1		Ω
SWITCH	ING PARAMETERS	•		•		
Q_g	Total Gate Charge			11.5		nC
Q_{gs}	Gate Source Charge	V _{GS} =10V, V _{DS} =480V, I _D =3.5A		4.8		nC
Q_{gd}	Gate Drain Charge			2.8		nC
T _{d(on)}	Turn-On DelayTime			18		ns
T _r	Turn-On Rise Time	V _{GS} =10V, V _{DS} =400V, I _D =3.5A,		9		ns
$T_{d(off)}$	Turn-Off DelayTime	$R_G=5\Omega$		30		ns
T _f	Turn-Off Fall Time			12		ns
T _{rr}	Body Diode Reverse Recovery Time			230		ns
I _{rm}	Peak Reverse Recovery Current	everse Recovery Current I _F =3.5A, dl/dt=100A/µs, V _{DS} =400V		16.5		Α
Q _{rr}	Body Diode Reverse Recovery Charge			2.5		μС

A. The value of R $_{\rm AJA}$ is measured with the device in a still air environment with T $_{\rm A}$ =25 $^{\circ}$ C.

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B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150° C, Ratings are based on low frequency and duty cycles to keep initial T_J =25° C.

D. The R _{BJA} is the sum of the thermal impedance from junction to case R _{BJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =150° C. The SOA curve provides a single pulse rating. G. L=60mH, I_{AS} =0.6A, R_G =25 Ω , Starting T_J =25° C.

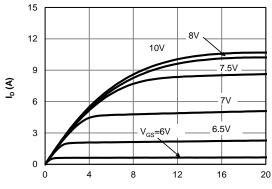
H. $C_{\text{o(er)}}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{\text{(BR)DSS}}$.

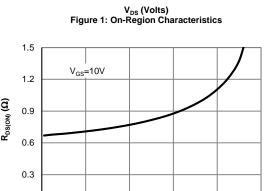
1. $C_{\text{o(tr)}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{\text{(BR)DSS}}$.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





 $\label{eq:local_local} I_{D}\left(\mathbf{A}\right)$ Figure 3: On-Resistance vs. Drain Current and Gate Voltage

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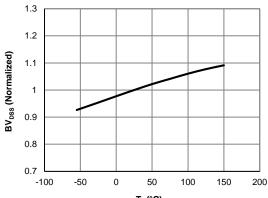
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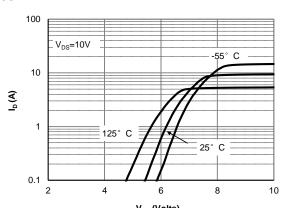
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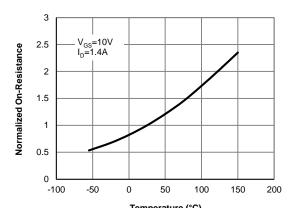
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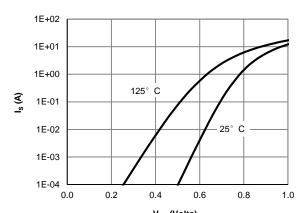
T_J (°C) Figure 5: Break Down vs. Junction Temparature



V_{GS} (Volts) Figure 2: Transfer Characteristics



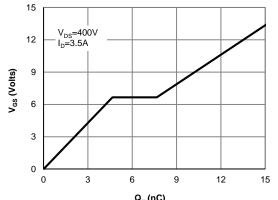
Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature



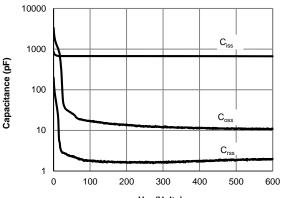
V_{SD} (Volts) Figure 6: Body-Diode Characteristics



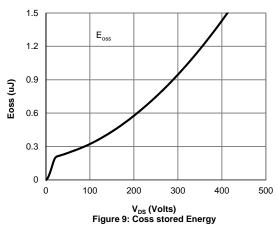
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

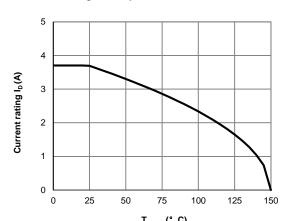


 ${\bf Q_g}$ (nC) Figure 7: Gate-Charge Characteristics

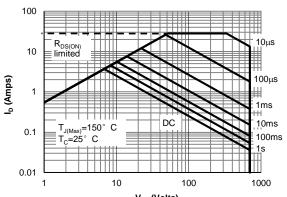


V_{DS} (Volts)
Figure 8: Capacitance Characteristics





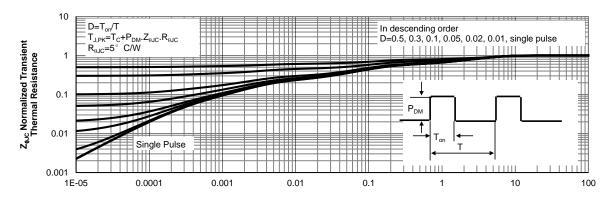
T_{CASE} (° C)
Figure 10: Current De-rating (Note F)



V_{DS} (Volts)
Figure 11: Maximum Forward Biased Safe Operating
Area (Note F)



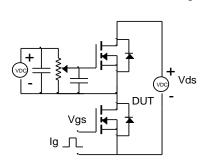
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

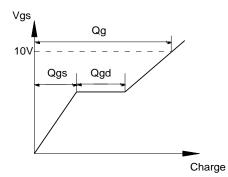


Pulse Width (s)
Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

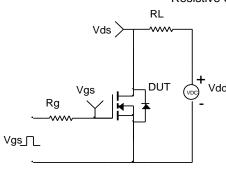


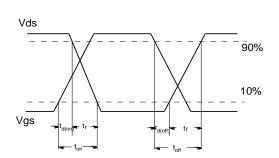
Gate Charge Test Circuit & Waveform



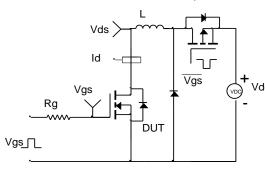


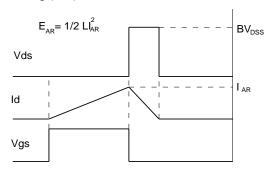
Resistive Switching Test Circuit & Waveforms



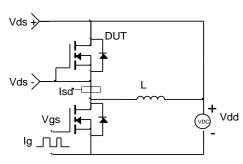


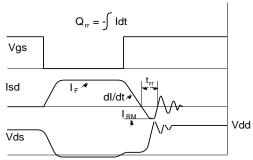
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms





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